

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Page Patent Application of:

INVENTORS: Oystol et al.

SERIAL NO.: 10/626,851 ART UNIT: Unknown FILED: 7/22/2003 EXAMINER: Unknown

TITLE: System For Measuring The Effect Of Errors In An Active Device

ATTORNEY DOCKET NO.: 904.0117.U1(US)

Commissioner For Trademarks P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to Sections 609 and 707.05(b) of the MPEP and 37 CFR 1.97-1.99, copies are herewith submitted of documents which may be pertinent to the invention as claimed in the above-identified application. The attached form PTO-1449 lists these documents.

The citation of these documents should not be construed as a representation that a thorough search has been made, or that other, more pertinent material is not available.

Respectfully submitted,

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Page No.: 1 of: 1

INFORMATION DISCLOSURE Docket No.: 901.0117.U1(US) CITATION FORM FOR PATENT APPLICATION

Serial No.: 10/626,851

Applicant(s): Oystol et al.

(FORM PTO-1449)		F::: D : 7/22/5	7/00/0003			
	(Substitute)	Filing Date: 7/22/2				
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Examiner Initials	Document Number (Country Code-Number-Kind Code)	Publication Date (MM-DD-YYYY)	Name Of Patentee of Applican	it	Translation Yes/No/n/a	
					100.110/110	
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